

Notice of References Cited		Application/Control No. 10/523,193	Applicant(s)/Patent Under Reexamination SHEN ET AL.	
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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2001/0033660 A1	10-2001	Maeda, Mitsu	380/232
*	B US-2001/0041061 A1	11-2001	Nakagawa, Toshiyuki	386/111
*	C US-2002/0035544 A1	03-2002	Wakao et al.	705/51
*	D US-2002/0156712 A1	10-2002	Rambhia, Avni Harilal	705/36
*	E US-2003/0016744 A1	01-2003	Nakagawa, Toshiyuki	375/240.01
*	F US-2003/0028397 A1	02-2003	Tagashira et al.	705/1
*	G US-2003/0118188 A1	06-2003	Collier et al.	380/277
*	H US-2003/0163430 A1	08-2003	Takaku, Masahiko	705/52
*	I US-6,643,330 B1	11-2003	Nakagawa et al.	375/240.28
*	J US-2003/0229900 A1	12-2003	Reisman, Richard	725/87
*	K US-2004/0031058 A1	02-2004	Reisman, Richard	725/112
*	L US-2005/0044016 A1	02-2005	Irwin et al.	705/030
*	M US-6,891,953 B1	05-2005	DeMello et al.	380/277

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
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		Examiner DAVID CERVETTI	Art Unit 2136	Page 2 of 2

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,931,541 B1	08-2005	Nakagawa, Toshiyuki	713/193
*	B US-2005/0262520 A1	11-2005	Burnett et al.	719/320
*	C US-6,970,849 B1	11-2005	DeMello et al.	705/52
*	D US-6,981,262 B1	12-2005	DeMello et al.	719/310
*	E US-7,099,473 B2	08-2006	Maeda, Mitsu	380/239
*	F US-7,099,491 B2	08-2006	Takaku, Masahiko	382/100
*	G US-7,158,953 B1	01-2007	DeMello et al.	705/51
*	H US-2007/0086664 A1	04-2007	Kim et al.	382/239
*	I US-7,231,043 B2	06-2007	Maeda, Mitsu	380/202
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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